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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Florence Eschbach et al.      Art Unit: 1773  
Serial No.: 10/649,354      Examiner: Vivian Chen  
Filed : August 26, 2003  
Assignee : Intel Corporation  
Title : ATTACHING A PELLICLE FRAME TO A RETICLE

**Mail Stop Amendment**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information Disclosure Statement and documents listed on form PTO-1449.

Each enclosed document listed on the herewith Form PTO-1449 was cited in the attached International Search Report dated August 25, 2005, issued in a foreign counterpart application not more than three months ago. To the best knowledge of the undersigned, this is the first citation of these items in any communication from a foreign patent office in a counterpart foreign application. No fee is required.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

October 12, 2005  
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Jennifer H. Payne  
Typed or Printed Name of Person Signing Certificate

Applicant : Florence Eschbach et al.  
Serial No. : 10/649,354  
Filed : August 26, 2003  
Page : 2 of 2

Attorney's Docket No.: 10559-887001 / P17697

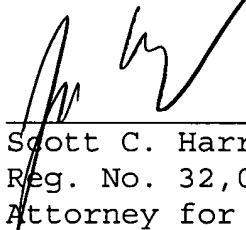
The documents are in the English language; hence no concise explanation is necessary per Rule 98(a)(3).

Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

Please apply any additional charges or credits to Deposit Account No. 06-1050.

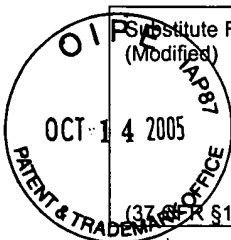
Respectfully submitted,

Date: October 12, 2005

  
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 Substitute Form PTO-1449  
 (Modified)

 U.S. Department of Commerce  
 Patent and Trademark Office

 Attorney's Docket No.  
 10559-887001

 Application No.  
 10/649,354

**Information Disclosure Statement  
 by Applicant**

(Use several sheets if necessary)

(37 CFR § 1.98(b))

 Applicant  
 Florence Eschbach et al.

 Filing Date  
 August 26, 2003

 Group Art Unit  
 1773

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AJ	0 942 325	09/1999	EPO				
	AK							
	AL							
	AM							
	AN							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AO	Chen, et al., "Pellicle-Induced Reticle Distortion: An Experimental Investigation", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 3546, pp. 167-172 (1998).
	AP	Cotte, et al., "Effects of Soft Pellicle Frame Curvature and Mounting Process on Pellicle-Induced Distortions in Advanced Photomasks", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 5040, pp. 1044-1054 (2003).
	AQ	Cotte, et al., "Experimental and Numerical Studies of the Effects of Materials and Attachment Conditions on Pellicle-Induced Distortions in Advanced Photomasks", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 4754, pp. 579-588 (2002).
	AR	Cotte, et al., "Numerical and Experimental Studies of Pellicle-Induced Photomask Distortions", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 4562, pp. 641-651 (2002).

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.